

21 Apr 00

04/09/03

10:38

7036414357

RSHT - FAIRFAX

001

# ReedSmith<sub>LLP</sub>

**TO** Examiner Timothy L. Rude  
**Company** U.S. Patent and Trademark Office  
**Fax** (703) 746-8745  
**Phone**

**FROM** Juan Carlos A. Marquez *Jennder, J*  
**Phone** 703.641.4289  
**Fax** 703.641.4340  
**Date** April 9, 2003

**Total Number of Pages Including Cover Page 4**

Original will follow via: ☐ Regular Mail ☐ Overnight Delivery ☐ Messenger ☐ None

COPIES TO: Name	Company	Fax	Phone

**NOTES:** Examiner Rude: Pursuant to our telephone conversation of March 27, 2003, regarding 09/822,175, attached herewith please find our comments, proposed claim amendment, revised translation and explanatory drawing. Should you have any questions, please feel free to contact us at your earliest convenience.

**If you do not receive all of the pages, please call at 703.641.**

Please Transmit Before: ☐ 9 ☐ 10 ☐ 11 a.m. ☐ 12 ☐ 1 ☐ 2 ☐ 3 ☐ 4 ☐ 5 ☐ 6 ☐ 7 ☐ 8 p.m.

Client Number: 999906 Matter Number: 00081 Attorney Number:

Transmission Time: a.m. p.m. Finish Time: a.m. p.m.

Operator:

**PLEASE NOTE:** The information contained in this facsimile message may be privileged and confidential, and is intended only for the use of the individual(s) or entity named above who has been specifically authorized to receive it. If the reader is not the intended recipient, you are hereby notified that any dissemination, distribution or copying of this communication is strictly prohibited. If you have received this communication in error, please notify us immediately by telephone and return all pages to the address shown below. Thank you.

Reed Smith LLP  
3110 Fairview Park Drive  
Suite 1400  
Falls Church, VA 22042  
703.641.4200  
Fax 703.641.4340  
Delaware  
New Jersey  
New York  
Pennsylvania  
Virginia  
Washington, DC

reedsmith.com

FXLUS-0100030.01-SPFISHER  
April 9, 2003 9:16 AM

Received from < 7036414357 > at 4/9/03 10:54:39 AM [Eastern Daylight Time]

Further to your telephone conversation with Ms. Jennifer Teng on March 27, 2003, we thank you for your willingness to communicate informally via telephone and to fax comments on issues relating to the application, including the different interpretations of the translation of the Japanese prior art reference to Misono. The proposed claim amendment and the translation of Misono's paragraphs [0015] and [0017] are enclosed. The term "buried" is recited (page 9, line 19) in the claim to distinguish the invention from Misono's spacers 9-11 which are not "buried" in the seal section 5. The recitation of "precisely disbursed" (page 9, line 23) and "at a desired location" (page 9, line 7) are inserted to distinguish the invention from Misono's spacers mixed in the sealant as described in the translation filed herewith.

Regarding Misono's spacers 9-11, they are surrounded by the wall of the seal section 5 (Fig. 1) thus placing them "in" or "within" the seal section 5. However, they are not "buried" in the seal section 5.

Regarding Misono's spacers mixed in the sealant, they are mixed in the sealant and carried to the substrate surface along with the mixture to be printed thereon. The spacers in the mixture then are squeezed and moved in the sealant while the substrates 1 and 2 are pressed towards each other to be adhered by the sealant. The positions of the spacers in the sealant are randomly decided after the squeezing step such that the spacers in sealant cannot be precisely dispersed at a desired location on the substrate in a manner similar to the spacers of the invention. An explanatory drawing is attached.

Each spacer of the invention is photolithographically formed (by selective etching, page 8, line 24 to page 9, line 4) to be precisely dispersed and buried within said seal material in a predetermined shape thereof at a desired location on either of said substrates. Each spacer is already fixed to the substrate before the sealant is printed to the substrate such that the spacer will not move when the substrates 1 and 2 are pressed to adhere with each other via the sealant.

Please confirm that you understand and perhaps agree with our analysis as described, and provide us with your comments. Please feel free to contact me at (703) 641-4289. We look forward to hearing from you soon.

Juan Marquez



Jennifer Tang  
x 4206